


<b>Search Notes</b>  	<b>Application/Control No.</b>  10551670	<b>Applicant(s)/Patent Under Reexamination</b>  MEDERSKI ET AL.
	<b>Examiner</b>  KRISTIN BIANCHI	<b>Art Unit</b>  1626

SEARCHED			
Class	Subclass	Date	Examiner
514	235.2	06/30/08	KB
514	235.5	06/30/08	KB
514	423	06/30/08	KB
544	141	06/30/08	KB
548	537	06/30/08	KB
548	538	06/30/08	KB
514	235.2	10/22/08	KB
514	235.5	10/22/08	KB
544	141	10/22/08	KB

SEARCH NOTES		
Search Notes	Date	Examiner
inventor name search (EAST)	06/27/08	KB
IDS/prior art (eDAN and EAST)	06/27/08	KB
STIC STN search results (EAST and NPL)	06/27/08	KB
patentability conferece	10/21/08	KB
updated search (EAST)	10/22/08	KB
interference search (EAST)	10/22/08	KB

INTERFERENCE SEARCH			
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514	235.2	10/22/08	KB
514	235.5	10/22/08	KB
544	141	10/22/08	KB

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